

文件编号HXA-L20-24(01)发行日期2015年11月05日

承认规格书

种类:功率电感

系列号: HXNR6045N-Series

客户料号:_____

李	客户承认栏
承认日期	年 月 日

(贵司承认后请签署一份返回华信安电子,谢谢!)

厦门华信安电子科技有限公司技术质量部

承 认	确 认	作 成
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Power Inductor

HXNR6045N-SERIES

		ECN HISTORY	LIST		
REV	DATE	DESCRIPTION	APPROVED	CHECKED	DRAWN
1.0	15/11/05	新 發 行	龙梅	梁峰	王亮
備 註					
山					

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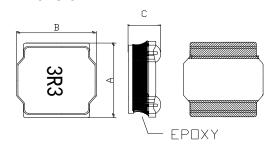
Power Inductor

HXNR6045N-SERIES

1. Features

- 1. This specification applies Low Profile Power Inductors.
- 2. 100% Lead(Pb) & Halogen-Free and RoHS compliant.

2. Dimension

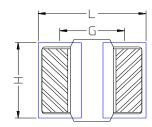


Series	A(mm)	B(mm)	C(mm)
HXNR6045N	6.0±0.3	6.0±0.3	4.2±0.3

Halogen-free



Recommendend Land pattern



L(mm)	G(mm)	H(mm)
6.5	4.25	4.8

3. Part Numbering

HXNR	6045	N	-	1 R0	Y
Α	В	С		D	Е

- A: Series
- B: Dimension
- C: Control S/N
- D: Inductance 1R0=1.0uH
- E: Inductance Tolerance $M=\pm20\%$; $Y=\pm30\%$

4. Specification

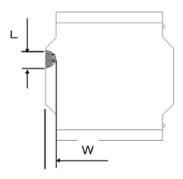
ISND Part Number	Inductance (uH)	Tolerance (%)	Test Frequency (Hz)	DCR (Ω) MAX	l sat (A)	I rms (A)
HXNR6045N-1R0Y	1.0	±30%	1V100K	0.018	9.85	5.80
HXNR6045N-1R5Y	1.5	±30%	1V100K	0.025	7.60	5.20
HXNR6045N-2R2Y	2.2	±30%	1V100K	0.030	6.00	4.90
HXNR6045N-3R3M	3.3	±20%	1V100K	0.035	5.25	3.70
HXNR6045N-4R7M	4.7	±20%	1V100K	0.038	5.00	3.50
HXNR6045N-5R6M	5.6	±20%	1V100K	0.042	4.40	3.15
HXNR6045N-6R8M	6.8	±20%	1V100K	0.060	3.80	3.00
HXNR6045N-100M	10	±20%	1V100K	0.068	3.20	2.45
HXNR6045N-150M	15	±20%	1V100K	0.095	2.60	2.05
HXNR6045N-220M	22	±20%	1V100K	0.125	2.55	1.80
HXNR6045N-330M	33	±20%	1V100K	0.188	1.65	1.40
HXNR6045N-470M	47	±20%	1V100K	0.300	1.30	1.25
HXNR6045N-680M	68	±20%	1V100K	0.450	1.00	0.85
HXNR6045N-101M	100	±20%	1V100K	0.680	0.80	0.55
HXNR6045N-102M	1000	±20%	1V100K	7.000	0.36	0.19

Note:

 $\mbox{lsat}: \mbox{Based on inductance change} \quad (\, \triangle \mbox{L/L0}: \, \underline{\le} \mbox{-30\%} \,) \, \, @ \mbox{ ambient temp. } 25 {}^{\circ}\!\! \mathbb{C}$

 $\label{eq:loss_trans} \textit{Irms}: \textit{Based on temperature rise} \quad (\triangle T:40\% \ \ \, \textit{typ.}) \qquad \pmb{www.xmisnd.com}$

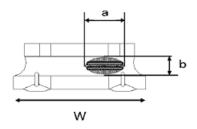
Core chipping



Туре	L	w
HXNR6045N	4.5mm Max.	4.5mm Max.

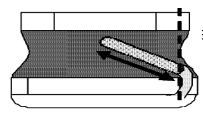
Void_appearance tolerance Limit

The appearance standard of the chipping size in top side, of bottom side ferrite core is following dimension. Size of voids occurring to coating resin is specified below.



External appearance criterion for exposed wire

Exposed end of the winding wire at the secondary side should be 3mm and below.



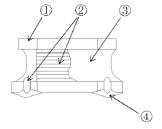
Exposed wire tolerance limit of coating resin part on product side.

Size of exposed wire occurring to coating resin is specified below.

- 1. Width direction (dimension a) : Acceptable when a \leq w/2 Nonconforming when a > w/2
- 2. Length direction (dimension b): Dimension b is not specified.
- 3. When total area of exposed wire occurring to each sides is not greater than 50% of coating resin area, that is acceptable.

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5. Material List



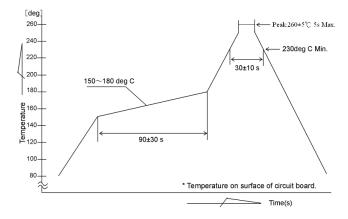
No.	Item	Material
1	Core	Ni-Zn ferrite
2	Wire	Copper Wire
3	Coating	Ероху
4	Solder	Lead free

6. Reliability and Test Condition

Item	Performance	Test Method and Remarks
Operating Temperature	- 25 ~ +125℃.	Including self-generated heat
Storage Temperature	-40 \sim +85 $^{\circ}$ C 5 to 40 $^{\circ}$ C for the product with taping.	
Rated current		
Inductance (L)	Within the specified tolerance	LCR Meter: HP 4285A or equivalent, 100kHz, 1V
DC Resistance		DC Ohmmeter: HIOKI3227 or equivalent
Temperature characteristics	Inductance change: Within±20%	Measurement of inductance shall be taken at temperature rang within–25°C to +85°C. With reference to inductance value at+20°C, change rate shall be calculated. Measurement of inductance shall be taken at temperature rang within–40°C to +125°C. With reference to inductance value at+20°C, change rate shall be calculated.
Resistance to flexure substrate	No damage.	The test samples shall be soldered to the testing board by the reflow. As illustrated below, apply force in the direction of the arrow indicating until deflection of the test board reaches to 2mm. Proced 200 Res 1002 Res 1002 Substrate size : 100x40x1.0 Substrate material : glass epoxy-resin Solder cream thickness : 0.15
Adhesion of Terminal electrode	Shall not come off PC board.	The test samples shall be soldered to the testing board and by the reflow. 10 N, 5 s Applied force: 10 N to X and Y directions. Duration: 5s Solder cream thickness: 0.15
Resistance to Vibration	Inductance change: Within±10% No abnormality observed in appearance.	The test samples shall be soldered to the test board by the reflow. Then it shall be submitted to below test conditions. Frequency: 10-55Hz Total Amplitude: 1.5mm (May not exceed acceleration 196m/S2) Sweeping Method:10Hz to 55Hz to 10Hz for 1min. Time: 2 hours each in X,Y, and Z Direction. Recovery: At least 2hrs of recovery under the standard condition after the test, followed by the measurement within 48hrs.
Solderability	At least 90% of surface of terminal electrode is covered by new solder.	The test samples shall be dipped in flux, and then immersed in molten solder as shown in below. Flux: methanol solution containing rosin 25% Solder temperature: $245\pm5^{\circ}$ C Time: 5 ± 1.0 sec. Immersion depth: All sides of mounting terminal shall be immersed.

Item	Performance	Test Method and Remarks			
Resistance to soldering	for 4 seco Test	for 40 second seconds,2 tim Test board thi	The test sample shall be exposed to reflow oven at 230±5°C for 40 seconds, with peak temperature at 260±5°C for 5 seconds, 2 times. Test board thickness: 1.0mm Test board material: glass epoxy-resin		
		reflow. The test samp for specified to sequence.	oles shall be soldered to oles shall be placed at time by step 1 to step 4 ure cycles shall be rep	specified tempera as shown below	ture in
Thermal shock		Phase	Temperature(℃)	Time(min.)	
		1	-40±3℃	30±3	
		2	RoomTemp	Within 3	1
		3	85±2℃	30±3	
		4	RoomTemp	Within 3	
Damp heat life test	Inductance change: Within±10% No abnormality observed in appearance.	Test Method and Remarks The test samples shall be soldered to the test board by the reflow. The test samples shall be placed in thermostatic oven se specified temperature and humidity as shown in below. Temperature: 60±2°C Humidity: 90–95%RH Time: 500+24/-0 hrs			
Loading under damp heat life test		reflow. The test samp specified temp current contine Temperature: Humidity: 90-	-95%RH nt: Rated current	thermostatic oven and applied the ra	set at
Low temperature life test		reflow.	-40±2℃		
Loading at high temperature life test		reflow. Temperature:	nt: Rated current	o the test board b	y the

7. Soldering



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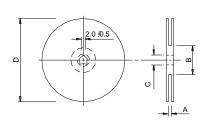
(2) Tape Dimension

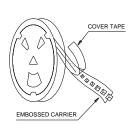
Туре

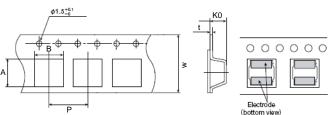
HXNR6045N

8. Packaging Information

(1) Reel Dimension







Ko(mm)

4.65±0.1

12.0±0.1

Ao(mm) Bo(mm)

(mm)	W(mm)	t(mm)
	Electrode (bottom view)	

Туре	A(mm)	B(mm)	C(mm)	D(mm)
HXNR6045N	16.4±2	100±4.0	13.2±0.2	330±2.0

(3) Packaging Quantity

Туре	Chip / Reel	
HXNR6045N	1000	

Application Notice

- Storage Conditions
- To maintain the solderability of terminal electrodes:
- 1. ISND products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
- 3. Recommended products should be used within 12 months form the time of delivery.
- 4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
- 1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

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单击下面可查看定价,库存,交付和生命周期等信息

>>ISND(华信安)